



Fraunhofer Institute for Reliability  
and Microintegration IZM

Electronic Packaging Days 2025

Rolf Aschenbrenner

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# Enabling the Future – APECS Pilot Line

# Strengthening Europe's technological leadership

## Pilotlines in Pillar 1

### Pillar 1

#### »Chips for Europe Initiative«

Strengthening research, development and innovation



NanoIC



### Pillar 2

#### »Security of Supply«

Support for new types of production facilities and EU foundries

### Pillar 3

#### »Monitoring and Crisis Response«

Coordination mechanism for monitoring the supply of semiconductors

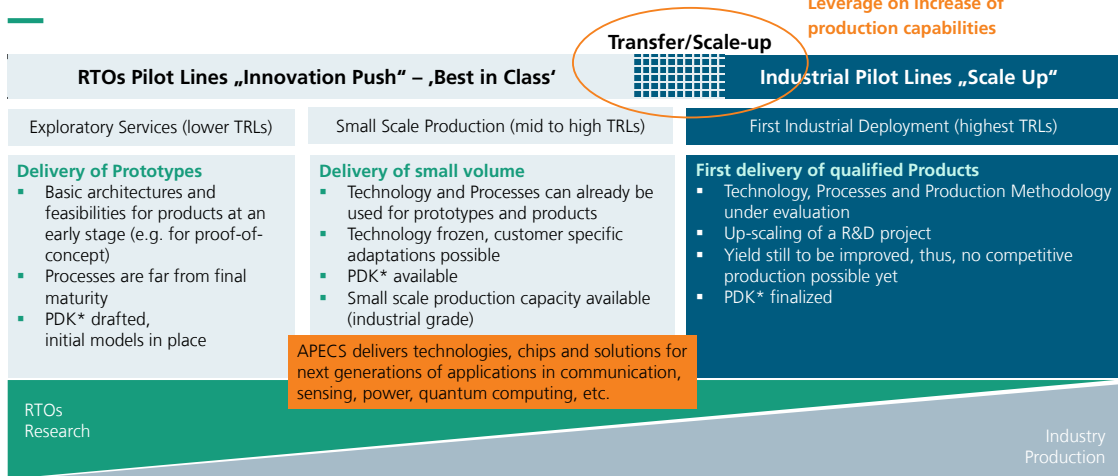


#### KEY FACTS

- Total Budget: 730 Mio EUR
- Project duration: Q4/2024 – Q2/2029
- Consortium: 10 partners from 8 European countries

# Pan European Pilot Line Facility: Categorization of Pilot Lines

## On Definition of RTO Pilot Line vs. Industrial Pilot Line



\* PDK: process design kit, model of the fabrication process to be used for the chip design

# European Infrastructure

## Pilotline for Advanced Packaging and Heterogeneous Integration for Electronic Components and Systems

### P/ADK Design Flows

STCO Design

### Interface Processing

#### Chiplet Integration

- Hetero-integration into (quasi-) monolithic integration
- Chiplet integration platform (2.5D and 3D)

### Analysis & Metrology

Characterization,  
Test & Reliability

### Users

- SMEs
- Start-ups
- System / Design Houses
- IDMs
- RTOs
- Universities

### Overall budget

730m  
app 500m CAPEX  
app 230m OPEX

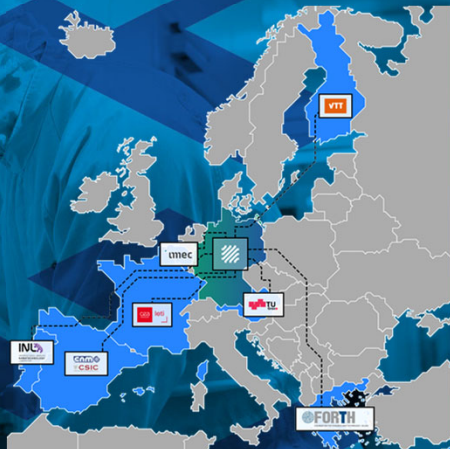
### Duration

12/24 - 12/29

### Funding

EU 50%  
BMFTR 33%  
Federal states 17%

Application Solution developed  
under the EU Green Deal



# APECS Pilotline

## Chiplet Integration Platform

### Chiplet Interface Readiness for Heterogeneous Integration

Chiplets from external partners (RTOs, IDMs, Foundries,...)

Compute and Memory Integration

MEMS Integration

Photonics Integration  
InP Tx Chiplets  
GaN/GaAs Laser

RF Integration  
InP-on-BiCMOS  
Chiplet BiCMOS-CMOS  
GaN-on-SiC HEMT /  
InGaAs-on-Si HEMT

Characterization Test Reliability

### Chiplet Integration Platforms

#### Functional Interposer

RF/Photonic/MEMS Interposer  
200 mm Si/Glas

Ultra High Density Interposer  
300 mm Si

Reticle Size Limitation  
Glass as an HD Option

Organic/Glass Interposer  
Up to 600 mm

Second Level Assembly

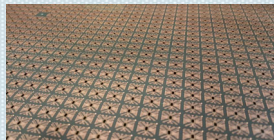
#### Toolbox for Functional Integration and Advanced Packaging

3D Stacks, Si-Bridge,  $\mu$ -Bumps, Embedding, Assembly, Package-on-Package, .....

#### Wafer Level Packaging (WLP)



#### Panel Level Packaging (PLP)



### APECS Demonstrators

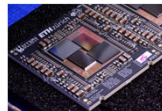
Demonstrator HPC

Demonstrator MEMS

Demonstrator Photonic

Demonstrator RF

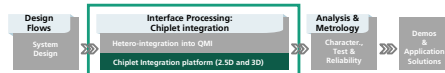
Characterization Test Reliability





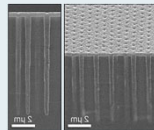
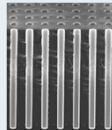
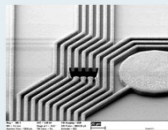
# Chiplet Integration Platform

## Functional Interposer



### Target

- Anorganic Interposers for advanced CMOS on 300mm
- Multi-Functional Interposers for RF, Optoelectronics & MEMS\*
- Passive Functionalities in Interposer
- Organic HD Interposers
- **Providing all required technologies for interposers based chiplet integration**



### Innovations

- Sub-micron TSV's, AR20:1, UHD Routing – incl. PostCMOS
- Glass, HR-Si, Ceramics with TxV's and resp. routing, on 200mm
- IPDs, integrated cooling, LWGs, structural features
- Advanced HD substrates (5µm L/S)
- Laminates with embedded IC
- Panel Scale Interposers using FO processes

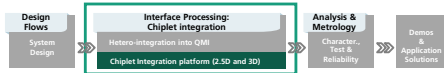
### Impact

- Preparation for UHD Wafer Scale Integration, supporting QMI and Advanced Packaging
- Interposers serving Multi-Domain Systems (MEMS, Opto, RF, Sensing, \*) for broad range of functionalities
- Critical functionalities integrated in a single process flow
- Module- and System Interfaces towards the applications

\* Power Electronics is served but was excluded from the text due to potential interference with the PowerSemiconductor Pilot Line

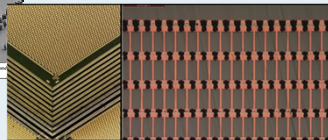
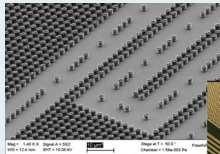
# Chiplet Integration Platform

## Functional Integration



### Target

- 3D Stacking of advanced CMOS wafers and non-CMOS heterogenous/multimaterial wafers
- 2.5D Integration of chiplets onto interposer
- Preparation for chiplet interfaces
- Specific technologies for MEMS and sensor chiplets
- **Providing all technologies to realize heterogeneously integrated modules**



### Innovations

- High density Wafer2Wafer stacking with sub  $\mu\text{m}$  precision using hybrid bonding
- Stack-integration of specific functionalities for HIC providing hermeticity, capping
- Die2Wafer integration for heterogenous functionalities
- Chiplet interface adaption with RDLs, terminal metal & bumps

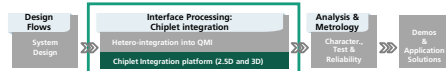
### Impact

- Chiplet based module realization with functionalities from different domains
- Highest density integration of heterogenous chiplets
- Enabling STCO methodology throughout domains



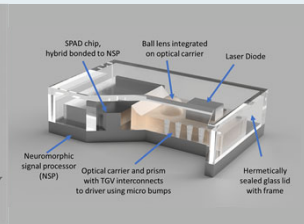
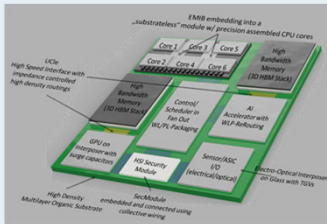
# Chiplet Integration Platform

## Advanced Packaging & Assembly



### Target

- System scale assembly for Heterosystems with Modules and Subsystems
- Quality and Reliability assured functionalities at system level
- Novel integration concepts for 3D volumetric systems



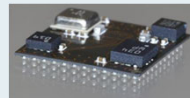
### Innovations

- High density, high speed, assembly on advanced substrates
- Reliable assembly for multi-layered heterogenous systems (L1-L3)
- Embedded and fan out integration of systems
- Hybrid integration concept using embedding and fan out on panel scale
- Layer-by-Layer stacking for 3D volumetric system integration



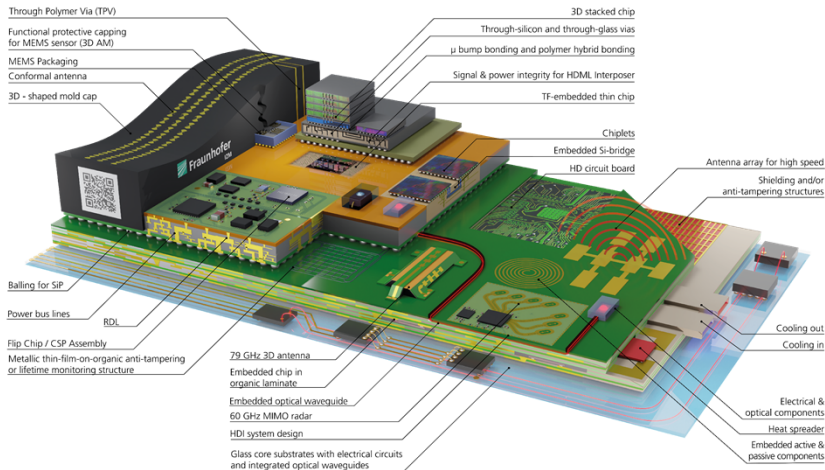
### Impact

- Functional highly integrated systems for novel applications like AI, autonomous mobility, RF and Communication, Sensors, Power and Photonics
- Supporting STCO methodology from L1-L3



# Hetero-Integration Technologies and Advanced Packaging

Bringing microelectronics into application



## Coordinated by



## Implemented by



## Pilot Line Project Partners



## Co-funded by



Co-funded by  
the European Union



APECS is co-funded by the Chips Joint Undertaking and national funding authorities of Austria, Belgium, Finland, France, Germany, Greece, Portugal, Spain, through the Chips for Europe Initiative.





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# Kontakt

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# Thank you for your attention

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